

<b>Notice of References Cited</b>	Application/Control No. 10/623,940	Applicant(s)/Patent Under Reexamination NAKAJIMA ET AL.	
	Examiner Nhan T. Tran	Art Unit 2622	Page 1 of 1

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*	B	US-2002/0041404	04-2002	Shinotsuka et al.	358/514
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	M	US-			

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**NON-PATENT DOCUMENTS**

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